

Search Notes**Application/Control No.**

10/647,762

Examiner

Paul D. Kim

Applicant(s)/Patent under Reexamination

HAN ET AL.

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	592.1 603.12- 603.16 603.18 829 831	8/30/2005	PK
	851 885		
360	121-126		
	317		
427	127 128		
451	5 41		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search EAST/NPL (IEEE)	8/31/2005	PK
Updated Text Search EAST/PGPub	1/20/2006	PK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPub text search see attachment			